

JT 5510 / JT 5550

JT 5510 TRANSIENT GENERATOR

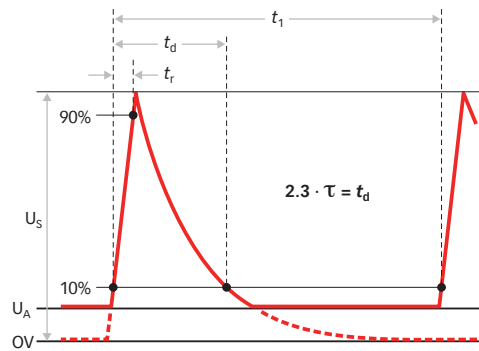
JT 5550 LOAD DUMP GENERATOR



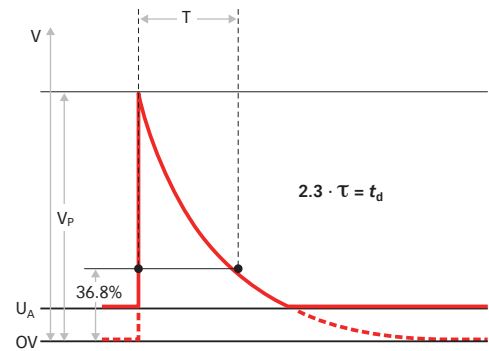
The JASO D001-94 from the Japanese Automotive Standards Organization departs from the traditional ISO/SAE pulses in significant ways. These pulses have a 1 μ s rise time, use special output impedances, methods of measuring pulse width, and pulse coupling. The JASO D001-94 forms the basis of other Japanese standards. This is one of a series of Gemini JASO based modules that was developed for usage with a NSG 5500 capacitive discharge immunity simulation system.

- Plug-in modules for JASO D001-94
- For many classic Japanese immunity tests
- Cost-effective addition to the NSG 5500 automotive transient generator

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These classic pulses are sometimes used as the base for other standards, Nissan for example. Therefore, other pulses are also covered by this module.

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Technical information JT 5510

Standard	Version	Year	Pulse name	Polarity	Amplitude		tr [μs]	td [μs]	Pulse width		Repetition rate	
					Min [V]	Max [V]			t [μs]	Ri [Ω]	Min [s]	Max [s]
JASO	D001-94	1994	Pulse A-2	positive	20	110	<1	5.75	2.5	0.4	1	120
JASO	D001-94	1994	Pulse D-2	positive	20	170	<1	5.75	2.5	0.9	1	120
JASO	D001-94	1994	Pulse B-1	negative	20	80	<1	138,000	60,000	8	6	120
JASO	D001-94	1994	Pulse B-2	negative	20	260	<1	4,600	2,000	80	6	120
JASO	D001-94	1994	Pulse E	negative	20	320	<1	60,000	26,000	210	30	120
Nissan	28400 NDS3	1997	Pulse B-1	positive	20	80	<1	46,000	*	*	3	120
Nissan	28402 NDS3	1997	Pulse B-2	negative	20	300	<1	7,600	*	*	3	120

Technical information JT 5550

Standard	Version	Year	Pulse name	Polarity	Amplitude		tr [μs]	td [μs]	Pulse width		Repetition rate	
					Min [V]	Max [V]			t [μs]	Ri [Ω]	Min [s]	Max [s]
JASO	D001-94	1994	Pulse A1	positive	50	110	<1	460	200	0.8	30	60
JASO	D001-94	1994	Pulse D1	positive	50	120	<1	920	400	1.5	30	60

* Pulse width values typical - defined by pulse generation circuit, not by pulse characteristics

Note: The pulse shaping networks are designed internally with a 1 μs rise time. However, due to system capacitance of the 100 A coupler, typical rise times measured at the output of the system can be 3 μs or more.

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